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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	1452
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	113
Number of Gates	24000
Voltage - Supply	3V ~ 3.6V, 4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TC)
Package / Case	144-LQFP
Supplier Device Package	144-TQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a54sx16p-1tq144m

Boundary Scan Testing (BST)

All SX devices are IEEE 1149.1 compliant. SX devices offer superior diagnostic and testing capabilities by providing Boundary Scan Testing (BST) and probing capabilities. These functions are controlled through the special test pins in conjunction with the program fuse. The functionality of each pin is described in Table 1-2. In the dedicated test mode, TCK, TDI, and TDO are dedicated pins and cannot be used as regular I/Os. In flexible mode, TMS should be set HIGH through a pull-up resistor of 10 k Ω . TMS can be pulled LOW to initiate the test sequence.

The program fuse determines whether the device is in dedicated or flexible mode. The default (fuse not blown) is flexible mode.

Table 1-2 • Boundary Scan Pin Functionality

Program Fuse Blown (Dedicated Test Mode)	Program Fuse Not Blown (Flexible Mode)
TCK, TDI, TDO are dedicated BST pins.	TCK, TDI, TDO are flexible and may be used as I/Os.
No need for pull-up resistor for TMS	Use a pull-up resistor of 10 k Ω on TMS.

Dedicated Test Mode

In Dedicated mode, all JTAG pins are reserved for BST; designers cannot use them as regular I/Os. An internal pull-up resistor is automatically enabled on both TMS and TDI pins, and the TMS pin will function as defined in the IEEE 1149.1 (JTAG) specification.

To select Dedicated mode, users need to reserve the JTAG pins in Actel's Designer software by checking the "Reserve JTAG" box in "Device Selection Wizard" (Figure 1-7). JTAG pins comply with LVTTTL/TTL I/O specification regardless of whether they are used as a user I/O or a JTAG I/O. Refer to the Table 1-5 on page 1-8 for detailed specifications.

Development Tool Support

The SX family of FPGAs is fully supported by both the Actel Libero® Integrated Design Environment (IDE) and Designer FPGA Development software. Actel Libero IDE is a design management environment, seamlessly integrating design tools while guiding the user through the design flow, managing all design and log files, and passing necessary design data among tools. Libero IDE allows users to integrate both schematic and HDL synthesis into a single flow and verify the entire design in a single environment. Libero IDE includes Synplify® for Actel from Synplicity®, ViewDraw® for Actel from Mentor Graphics®, ModelSim® HDL Simulator from Mentor Graphics, WaveFormer Lite™ from SynaptiCAD™, and Designer software from Actel. Refer to the Libero IDE flow diagram (located on the Actel website) for more information.

Actel Designer software is a place-and-route tool and provides a comprehensive suite of backend support tools for FPGA development. The Designer software includes timing-driven place-and-route, and a world-class integrated static timing analyzer and constraints editor. With the Designer software, a user can select and lock package pins while only minimally impacting the results of place-and-route. Additionally, the back-annotation flow is compatible with all the major simulators, and the simulation results can be cross-probed with Silicon Explorer II, Actel integrated verification and logic analysis tool. Another tool included in the Designer software is the SmartGen core generator, which easily creates popular and commonly used logic functions for implementation into your schematic or HDL design. Actel Designer software is compatible with the most popular FPGA design entry and verification tools from companies such as Mentor Graphics, Synplicity, Synopsys®, and Cadence® Design Systems. The Designer software is available for both the Windows® and UNIX® operating systems.

Probe Circuit Control Pins

The Silicon Explorer II tool uses the boundary scan ports (TDI, TCK, TMS, and TDO) to select the desired nets for verification. The selected internal nets are assigned to the PRA/PRB pins for observation. Figure 1-8 on page 1-7 illustrates the interconnection between Silicon Explorer II and the FPGA to perform in-circuit verification.

Design Considerations

The TDI, TCK, TDO, PRA, and PRB pins should not be used as input or bidirectional ports. Because these pins are active during probing, critical signals input through these pins are not available while probing. In addition, the Security Fuse should not be programmed because doing so disables the Probe Circuitry.

Figure 1-7 • Device Selection Wizard

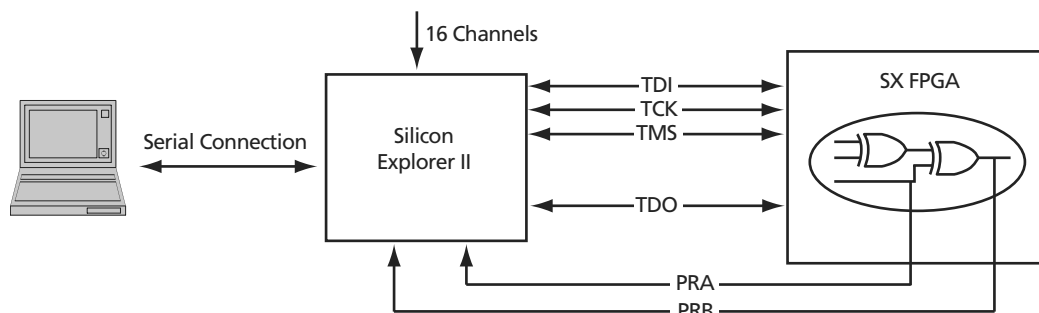


Figure 1-8 • Probe Setup

Programming

Device programming is supported through Silicon Sculptor series of programmers. In particular, Silicon Sculptor II are compact, robust, single-site and multi-site device programmer for the PC.

With standalone software, Silicon Sculptor II allows concurrent programming of multiple units from the same PC, ensuring the fastest programming times possible. Each fuse is subsequently verified by Silicon Sculptor II to insure correct programming. In addition, integrity tests ensure that no extra fuses are programmed. Silicon Sculptor II also provides extensive hardware self-testing capability.

The procedure for programming an SX device using Silicon Sculptor II are as follows:

1. Load the .AFM file
2. Select the device to be programmed
3. Begin programming

When the design is ready to go to production, Actel offers device volume-programming services either through distribution partners or via in-house programming from the factory.

For more details on programming SX devices, refer to the *Programming Antifuse Devices* application note and the *Silicon Sculptor II User's Guide*.

3.3 V / 5 V Operating Conditions

Table 1-3 • Absolute Maximum Ratings¹

Symbol	Parameter	Limits	Units
V_{CCR}^2	DC Supply Voltage ³	-0.3 to + 6.0	V
V_{CCA}^2	DC Supply Voltage	-0.3 to + 4.0	V
V_{CCI}^2	DC Supply Voltage (A54SX08, A54SX16, A54SX32)	-0.3 to + 4.0	V
V_{CCI}^2	DC Supply Voltage (A54SX16P)	-0.3 to + 6.0	V
V_I	Input Voltage	-0.5 to + 5.5	V
V_O	Output Voltage	-0.5 to + 3.6	V
I_{IO}	I/O Source Sink Current ³	-30 to + 5.0	mA
T_{STG}	Storage Temperature	-65 to +150	°C

Notes:

1. Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Device should not be operated outside the Recommended Operating Conditions.
2. V_{CCR} in the A54SX16P must be greater than or equal to V_{CCI} during power-up and power-down sequences and during normal operation.
3. Device inputs are normally high impedance and draw extremely low current. However, when input voltage is greater than $V_{CC} + 0.5$ V or less than $GND - 0.5$ V, the internal protection diodes will forward-bias and can draw excessive current.

Table 1-4 • Recommended Operating Conditions

Parameter	Commercial	Industrial	Military	Units
Temperature Range*	0 to + 70	–40 to + 85	–55 to +125	°C
3.3 V Power Supply Tolerance	±10	±10	±10	%V _{CC}
5.0 V Power Supply Tolerance	±5	±10	±10	%V _{CC}

Note: *Ambient temperature (T_A) is used for commercial and industrial; case temperature (T_C) is used for military.

Table 1-5 • Electrical Specifications

Symbol	Parameter	Commercial		Industrial		Units
		Min.	Max.	Min.	Max.	
V _{OH}	(I _{OH} = –20 μ A) (CMOS) (I _{OH} = –8 mA) (TTL) (I _{OH} = –6 mA) (TTL)	(V _{CCI} – 0.1) 2.4	V _{CCI} V _{CCI}	(V _{CCI} – 0.1) 2.4	V _{CCI} V _{CCI}	V
V _{OL}	(I _{OL} = 20 μ A) (CMOS) (I _{OL} = 12 mA) (TTL) (I _{OL} = 8 mA) (TTL)		0.10 0.50		0.50	V
V _{IL}			0.8		0.8	V
V _{IH}		2.0		2.0		V
t _R , t _F	Input Transition Time t _R , t _F		50		50	ns
C _{IO}	C _{IO} I/O Capacitance		10		10	pF
I _{CC}	Standby Current, I _{CC}		4.0		4.0	mA
I _{CC(D)}	I _{CC(D)} I _{Dynamic} V _{CC} Supply Current	See "Evaluating Power in SX Devices" on page 1-16.				

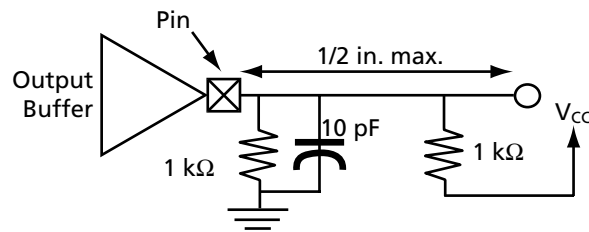
A54SX16P AC Specifications for (PCI Operation)

Table 1-7 • A54SX16P AC Specifications for (PCI Operation)

Symbol	Parameter	Condition	Min.	Max.	Units
$I_{OH(AC)}$	Switching Current High	$0 < V_{OUT} \leq 1.4^1$	-44		mA
		$1.4 \leq V_{OUT} < 2.4^1, ^2$	$-44 + (V_{OUT} - 1.4)/0.024$		mA
		$3.1 < V_{OUT} < V_{CC}^{1, ^3}$		EQ 1-1 on page 1-11	
	(Test Point)	$V_{OUT} = 3.1^3$		-142	mA
$I_{OL(AC)}$	Switching Current High	$V_{OUT} \geq 2.2^1$	95		mA
		$2.2 > V_{OUT} > 0.55^1$	$V_{OUT}/0.023$		
		$0.71 > V_{OUT} > 0^{1, ^3}$		EQ 1-2 on page 1-11	mA
	(Test Point)	$V_{OUT} = 0.71^3$		206	mA
I_{CL}	Low Clamp Current	$-5 < V_{IN} \leq -1$	$-25 + (V_{IN} + 1)/0.015$		mA
$slew_R$	Output Rise Slew Rate	0.4 V to 2.4 V load ⁴	1	5	V/ns
$slew_F$	Output Fall Slew Rate	2.4 V to 0.4 V load ⁴	1	5	V/ns

Notes:

1. Refer to the *V_I* curves in Figure 1-9 on page 1-11. Switching current characteristics for REQ# and GNT# are permitted to be one half of that specified here; i.e., half-size output drivers may be used on these signals. This specification does not apply to CLK and RST#, which are system outputs. "Switching Current High" specifications are not relevant to SERR#, INTA#, INTB#, INTC#, and INTD#, which are open drain outputs.
2. Note that this segment of the minimum current curve is drawn from the AC drive point directly to the DC drive point rather than toward the voltage rail (as is done in the pull-down curve). This difference is intended to allow for an optional N-channel pull-up.
3. Maximum current requirements must be met as drivers pull beyond the last step voltage. Equations defining these maxima (A and B) are provided with the respective diagrams in Figure 1-9 on page 1-11. The equation defined maxima should be met by design. In order to facilitate component testing, a maximum current test point is defined for each side of the output driver.
4. This parameter is to be interpreted as the cumulative edge rate across the specified range, rather than the instantaneous rate at any point within the transition range. The specified load (diagram below) is optional; i.e., the designer may elect to meet this parameter with an unloaded output per revision 2.0 of the PCI Local Bus Specification. However, adherence to both maximum and minimum parameters is now required (the maximum is no longer simply a guideline). Since adherence to the maximum slew rate was not required prior to revision 2.1 of the specification, there may be components in the market for some time that have faster edge rates; therefore, motherboard designers must bear in mind that rise and fall times faster than this specification could occur, and should ensure that signal integrity modeling accounts for this. Rise slew rate does not apply to open drain outputs.



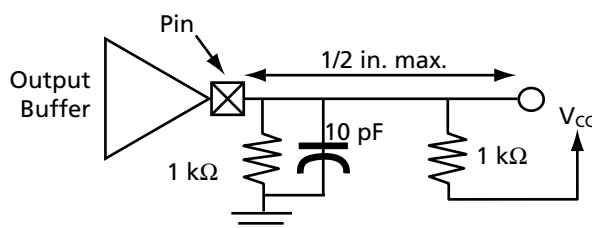
A54SX16P AC Specifications (3.3 V PCI Operation)

Table 1-9 • A54SX16P AC Specifications (3.3 V PCI Operation)

Symbol	Parameter	Condition	Min.	Max.	Units
$I_{OH(AC)}$	Switching Current High	$0 < V_{OUT} \leq 0.3V_{CC}^1$			mA
		$0.3V_{CC} \leq V_{OUT} < 0.9V_{CC}^1$	$-12V_{CC}$		mA
		$0.7V_{CC} < V_{OUT} < V_{CC}^{1,2}$	$-17.1 + (V_{CC} - V_{OUT})$	EQ 1-3 on page 1-14	
	(Test Point)	$V_{OUT} = 0.7V_{CC}^2$		$-32V_{CC}$	mA
$I_{OL(AC)}$	Switching Current High	$V_{CC} > V_{OUT} \geq 0.6V_{CC}^1$			mA
		$0.6V_{CC} > V_{OUT} > 0.1V_{CC}^1$	$16V_{CC}$		mA
		$0.18V_{CC} > V_{OUT} > 0^{1,2}$	$26.7V_{OUT}$	EQ 1-4 on page 1-14	mA
	(Test Point)	$V_{OUT} = 0.18V_{CC}^2$		$38V_{CC}$	
I_{CL}	Low Clamp Current	$-3 < V_{IN} \leq -1$	$-25 + (V_{IN} + 1)/0.015$		mA
I_{CH}	High Clamp Current	$-3 < V_{IN} \leq -1$	$25 + (V_{IN} - V_{OUT} - 1)/0.015$		mA
$slew_R$	Output Rise Slew Rate ³	0.2V _{CC} to 0.6V _{CC} load	1	4	V/ns
$slew_F$	Output Fall Slew Rate ³	0.6V _{CC} to 0.2V _{CC} load	1	4	V/ns

Notes:

1. Refer to the V/I curves in Figure 1-10 on page 1-14. Switching current characteristics for REQ# and GNT# are permitted to be one half of that specified here; i.e., half size output drivers may be used on these signals. This specification does not apply to CLK and RST# which are system outputs. "Switching Current High" specification are not relevant to SERR#, INTA#, INTB#, INTC#, and INTD# which are open drain outputs.
2. Maximum current requirements must be met as drivers pull beyond the last step voltage. Equations defining these maximums (C and D) are provided with the respective diagrams in Figure 1-10 on page 1-14. The equation defined maxima should be met by design. In order to facilitate component testing, a maximum current test point is defined for each side of the output driver.
3. This parameter is to be interpreted as the cumulative edge rate across the specified range, rather than the instantaneous rate at any point within the transition range. The specified load (diagram below) is optional; i.e., the designer may elect to meet this parameter with an unloaded output per the latest revision of the PCI Local Bus Specification. However, adherence to both maximum and minimum parameters is required (the maximum is no longer simply a guideline). Rise slew rate does not apply to open drain outputs.



Power-Up Sequencing

Table 1-10 • Power-Up Sequencing

V _{CCA}	V _{CCR}	V _{CCI}	Power-Up Sequence	Comments
A54SX08, A54SX16, A54SX32				
3.3 V	5.0 V	3.3 V	5.0 V First 3.3 V Second	No possible damage to device
			3.3 V First 5.0 V Second	Possible damage to device
A54SX16P				
3.3 V	3.3 V	3.3 V	3.3 V Only	No possible damage to device
3.3 V	5.0 V	3.3 V	5.0 V First 3.3 V Second	No possible damage to device
			3.3 V First 5.0 V Second	Possible damage to device
3.3 V	5.0 V	5.0 V	5.0 V First 3.3 V Second	No possible damage to device
			3.3 V First 5.0 V Second	No possible damage to device

Note: No inputs should be driven (high or low) before completion of power-up.

Power-Down Sequencing

Table 1-11 • Power-Down Sequencing

V _{CCA}	V _{CCR}	V _{CCI}	Power-Down Sequence	Comments
A54SX08, A54SX16, A54SX32				
3.3 V	5.0 V	3.3 V	5.0 V First 3.3 V Second	Possible damage to device
			3.3 V First 5.0 V Second	No possible damage to device
A54SX16P				
3.3 V	3.3 V	3.3 V	3.3 V Only	No possible damage to device
3.3 V	5.0 V	3.3 V	5.0 V First 3.3 V Second	Possible damage to device
			3.3 V First 5.0 V Second	No possible damage to device
3.3 V	5.0 V	5.0 V	5.0 V First 3.3 V Second	No possible damage to device
			3.3 V First 5.0 V Second	No possible damage to device

Note: No inputs should be driven (high or low) after the beginning of the power-down sequence.

Table 1-13 shows capacitance values for various devices.

Table 1-13 • Capacitance Values for Devices

	A545X08	A545X16	A545X16P	A545X32
C_{EQM} (pF)	4.0	4.0	4.0	4.0
C_{EQI} (pF)	3.4	3.4	3.4	3.4
C_{EQO} (pF)	4.7	4.7	4.7	4.7
C_{EQCR} (pF)	1.6	1.6	1.6	1.6
C_{EQHV}	0.615	0.615	0.615	0.615
C_{EQHF}	60	96	96	140
r_1 (pF)	87	138	138	171
r_2 (pF)	87	138	138	171

Table 1-14 • Power Consumption Guidelines

Description	Power Consumption Guideline
Logic Modules (m)	20% of modules
Inputs Switching (n)	# inputs/4
Outputs Switching (p)	# outputs/4
First Routed Array Clock Loads (q_1)	20% of register cells
Second Routed Array Clock Loads (q_2)	20% of register cells
Load Capacitance (C_L)	35 pF
Average Logic Module Switching Rate (f_m)	$f/10$
Average Input Switching Rate (f_n)	$f/5$
Average Output Switching Rate (f_p)	$f/10$
Average First Routed Array Clock Rate (f_{q1})	$f/2$
Average Second Routed Array Clock Rate (f_{q2})	$f/2$
Average Dedicated Array Clock Rate (f_{s1})	f
Dedicated Clock Array Clock Loads (s_1)	20% of regular modules

Follow the steps below to estimate power consumption. The values provided for the sample calculation below are for the shift register design above. This method for estimating power consumption is conservative and the actual power consumption of your design may be less than the estimated power consumption.

The total power dissipation for the SX family is the sum of the AC power dissipation and the DC power dissipation.

$$P_{\text{Total}} = P_{\text{AC}} (\text{dynamic power}) + P_{\text{DC}} (\text{static power})$$

EQ 1-9

Guidelines for Calculating Power Consumption

The power consumption guidelines are meant to represent worst-case scenarios so that they can be generally used to predict the upper limits of power dissipation. These guidelines are shown in Table 1-14.

Sample Power Calculation

One of the designs used to characterize the SX family was a 528 bit serial-in, serial-out shift register. The design utilized 100 percent of the dedicated flip-flops of an A545X16P device. A pattern of 0101... was clocked into the device at frequencies ranging from 1 MHz to 200 MHz. Shifting in a series of 0101... caused 50 percent of the flip-flops to toggle from low to high at every clock cycle.

AC Power Dissipation

$$P_{\text{AC}} = P_{\text{Module}} + P_{\text{RCLKA Net}} + P_{\text{RCLKB Net}} + P_{\text{HCLK Net}} + P_{\text{Output Buffer}} + P_{\text{Input Buffer}}$$

EQ 1-10

$$P_{\text{AC}} = V_{\text{CCA}}^2 \times [(m \times C_{\text{EQM}} \times f_m)_{\text{Module}} + (n \times C_{\text{EQI}} \times f_n)_{\text{Input Buffer}} + (p \times (C_{\text{EQO}} + C_L) \times f_p)_{\text{Output Buffer}} + (0.5 (q_1 \times C_{\text{EQCR}} \times f_{q1}) + (r_1 \times f_{q1}))_{\text{RCLKA}} + (0.5 (q_2 \times C_{\text{EQCR}} \times f_{q2}) + (r_2 \times f_{q2}))_{\text{RCLKB}} + (0.5 (s_1 \times C_{\text{EQHV}} \times f_{s1}) + (C_{\text{EQHF}} \times f_{s1}))_{\text{HCLK}}]$$

EQ 1-11

Table 1-18 • A54SX16 Timing Characteristics (Continued)
(Worst-Case Commercial Conditions, $V_{CCR} = 4.75\text{ V}$, $V_{CCA}, V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Network										
t _{HCKH}	Input LOW to HIGH (pad to R-Cell input)	1.2		1.4		1.5		1.8		ns
t _{HCKL}	Input HIGH to LOW (pad to R-Cell input)	1.2		1.4		1.6		1.9		ns
t _{HPWH}	Minimum Pulse Width HIGH	1.4		1.6		1.8		2.1		ns
t _{HPWL}	Minimum Pulse Width LOW	1.4		1.6		1.8		2.1		ns
t _{HCKSW}	Maximum Skew	0.2		0.2		0.3		0.3		ns
t _{HP}	Minimum Period	2.7		3.1		3.6		4.2		ns
f _{HMAX}	Maximum Frequency	350		320		280		240		MHz
Routed Array Clock Networks										
t _{RCKH}	Input LOW to HIGH (light load) (pad to R-Cell input)	1.6		1.8		2.1		2.5		ns
t _{RCKL}	Input HIGH to LOW (light load) (pad to R-Cell input)	1.8		2.0		2.3		2.7		ns
t _{RCKH}	Input LOW to HIGH (50% load) (pad to R-Cell input)	1.8		2.1		2.5		2.8		ns
t _{RCKL}	Input HIGH to LOW (50% load) (pad to R-Cell input)	2.0		2.2		2.5		3.0		ns
t _{RCKH}	Input LOW to HIGH (100% load) (pad to R-Cell input)	1.8		2.1		2.4		2.8		ns
t _{RCKL}	Input HIGH to LOW (100% load) (pad to R-Cell input)	2.0		2.2		2.5		3.0		ns
t _{RPWH}	Min. Pulse Width HIGH	2.1		2.4		2.7		3.2		ns
t _{RPWL}	Min. Pulse Width LOW	2.1		2.4		2.7		3.2		ns
t _{RCKSW}	Maximum Skew (light load)	0.5		0.5		0.5		0.7		ns
t _{RCKSW}	Maximum Skew (50% load)	0.5		0.6		0.7		0.8		ns
t _{RCKSW}	Maximum Skew (100% load)	0.5		0.6		0.7		0.8		ns
TTL Output Module Timing ³										
t _{DLH}	Data-to-Pad LOW to HIGH	1.6		1.9		2.1		2.5		ns
t _{DHL}	Data-to-Pad HIGH to LOW	1.6		1.9		2.1		2.5		ns
t _{ENZL}	Enable-to-Pad, Z to L	2.1		2.4		2.8		3.2		ns
t _{ENZH}	Enable-to-Pad, Z to H	2.3		2.7		3.1		3.6		ns
t _{ENLZ}	Enable-to-Pad, L to Z	1.4		1.7		1.9		2.2		ns
t _{ENHZ}	Enable-to-Pad, H to Z	1.3		1.5		1.7		2.0		ns

Notes:

- For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.
- Delays based on 35 pF loading, except t_{ENZL} and t_{ENZH} . For t_{ENZL} and t_{ENZH} , the loading is 5 pF.

Table 1-19 • A54SX16P Timing Characteristics (Continued)
(Worst-Case Commercial Conditions, $V_{CCR} = 4.75\text{ V}$, $V_{CCA}, V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
TTL/PCI Output Module Timing										
t _{DLH}	Data-to-Pad LOW to HIGH	1.5		1.7		2.0		2.3		ns
t _{DHL}	Data-to-Pad HIGH to LOW	1.9		2.2		2.4		2.9		ns
t _{ENZL}	Enable-to-Pad, Z to L	2.3		2.6		3.0		3.5		ns
t _{ENZH}	Enable-to-Pad, Z to H	1.5		1.7		1.9		2.3		ns
t _{ENLZ}	Enable-to-Pad, L to Z	2.7		3.1		3.5		4.1		ns
t _{ENHZ}	Enable-to-Pad, H to Z	2.9		3.3		3.7		4.4		ns
PCI Output Module Timing ³										
t _{DLH}	Data-to-Pad LOW to HIGH	1.8		2.0		2.3		2.7		ns
t _{DHL}	Data-to-Pad HIGH to LOW	1.7		2.0		2.2		2.6		ns
t _{ENZL}	Enable-to-Pad, Z to L	0.8		1.0		1.1		1.3		ns
t _{ENZH}	Enable-to-Pad, Z to H	1.2		1.2		1.5		1.8		ns
t _{ENLZ}	Enable-to-Pad, L to Z	1.0		1.1		1.3		1.5		ns
t _{ENHZ}	Enable-to-Pad, H to Z	1.1		1.3		1.5		1.7		ns
TTL Output Module Timing										
t _{DLH}	Data-to-Pad LOW to HIGH	2.1		2.5		2.8		3.3		ns
t _{DHL}	Data-to-Pad HIGH to LOW	2.0		2.3		2.6		3.1		ns
t _{ENZL}	Enable-to-Pad, Z to L	2.5		2.9		3.2		3.8		ns
t _{ENZH}	Enable-to-Pad, Z to H	3.0		3.5		3.9		4.6		ns
t _{ENLZ}	Enable-to-Pad, L to Z	2.3		2.7		3.1		3.6		ns
t _{ENHZ}	Enable-to-Pad, H to Z	2.9		3.3		3.7		4.4		ns

Note:

1. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.
3. Delays based on 10 pF loading.

208-Pin PQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
1	GND	GND	GND
2	TDI, I/O	TDI, I/O	TDI, I/O
3	I/O	I/O	I/O
4	NC	I/O	I/O
5	I/O	I/O	I/O
6	NC	I/O	I/O
7	I/O	I/O	I/O
8	I/O	I/O	I/O
9	I/O	I/O	I/O
10	I/O	I/O	I/O
11	TMS	TMS	TMS
12	V _{CCI}	V _{CCI}	V _{CCI}
13	I/O	I/O	I/O
14	NC	I/O	I/O
15	I/O	I/O	I/O
16	I/O	I/O	I/O
17	NC	I/O	I/O
18	I/O	I/O	I/O
19	I/O	I/O	I/O
20	NC	I/O	I/O
21	I/O	I/O	I/O
22	I/O	I/O	I/O
23	NC	I/O	I/O
24	I/O	I/O	I/O
25	V _{CCR}	V _{CCR}	V _{CCR}
26	GND	GND	GND
27	V _{CCA}	V _{CCA}	V _{CCA}
28	GND	GND	GND
29	I/O	I/O	I/O
30	I/O	I/O	I/O
31	NC	I/O	I/O
32	I/O	I/O	I/O
33	I/O	I/O	I/O
34	I/O	I/O	I/O
35	NC	I/O	I/O
36	I/O	I/O	I/O

208-Pin PQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
37	I/O	I/O	I/O
38	I/O	I/O	I/O
39	NC	I/O	I/O
40	V _{CCI}	V _{CCI}	V _{CCI}
41	V _{CCA}	V _{CCA}	V _{CCA}
42	I/O	I/O	I/O
43	I/O	I/O	I/O
44	I/O	I/O	I/O
45	I/O	I/O	I/O
46	I/O	I/O	I/O
47	I/O	I/O	I/O
48	NC	I/O	I/O
49	I/O	I/O	I/O
50	NC	I/O	I/O
51	I/O	I/O	I/O
52	GND	GND	GND
53	I/O	I/O	I/O
54	I/O	I/O	I/O
55	I/O	I/O	I/O
56	I/O	I/O	I/O
57	I/O	I/O	I/O
58	I/O	I/O	I/O
59	I/O	I/O	I/O
60	V _{CCI}	V _{CCI}	V _{CCI}
61	NC	I/O	I/O
62	I/O	I/O	I/O
63	I/O	I/O	I/O
64	NC	I/O	I/O
65*	I/O	I/O	NC*
66	I/O	I/O	I/O
67	NC	I/O	I/O
68	I/O	I/O	I/O
69	I/O	I/O	I/O
70	NC	I/O	I/O
71	I/O	I/O	I/O
72	I/O	I/O	I/O

Note: * Note that Pin 65 in the A54SX32—PQ208 is a no connect (NC).

208-Pin PQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
145	V _{CCA}	V _{CCA}	V _{CCA}
146	GND	GND	GND
147	I/O	I/O	I/O
148	V _{CCI}	V _{CCI}	V _{CCI}
149	I/O	I/O	I/O
150	I/O	I/O	I/O
151	I/O	I/O	I/O
152	I/O	I/O	I/O
153	I/O	I/O	I/O
154	I/O	I/O	I/O
155	NC	I/O	I/O
156	NC	I/O	I/O
157	GND	GND	GND
158	I/O	I/O	I/O
159	I/O	I/O	I/O
160	I/O	I/O	I/O
161	I/O	I/O	I/O
162	I/O	I/O	I/O
163	I/O	I/O	I/O
164	V _{CCI}	V _{CCI}	V _{CCI}
165	I/O	I/O	I/O
166	I/O	I/O	I/O
167	NC	I/O	I/O
168	I/O	I/O	I/O
169	I/O	I/O	I/O
170	NC	I/O	I/O
171	I/O	I/O	I/O
172	I/O	I/O	I/O
173	NC	I/O	I/O
174	I/O	I/O	I/O
175	I/O	I/O	I/O
176	NC	I/O	I/O
177	I/O	I/O	I/O
178	I/O	I/O	I/O
179	I/O	I/O	I/O
180	CLKA	CLKA	CLKA

208-Pin PQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
181	CLKB	CLKB	CLKB
182	V _{CCR}	V _{CCR}	V _{CCR}
183	GND	GND	GND
184	V _{CCA}	V _{CCA}	V _{CCA}
185	GND	GND	GND
186	PRA, I/O	PRA, I/O	PRA, I/O
187	I/O	I/O	I/O
188	I/O	I/O	I/O
189	NC	I/O	I/O
190	I/O	I/O	I/O
191	I/O	I/O	I/O
192	NC	I/O	I/O
193	I/O	I/O	I/O
194	I/O	I/O	I/O
195	NC	I/O	I/O
196	I/O	I/O	I/O
197	I/O	I/O	I/O
198	NC	I/O	I/O
199	I/O	I/O	I/O
200	I/O	I/O	I/O
201	V _{CCI}	V _{CCI}	V _{CCI}
202	NC	I/O	I/O
203	NC	I/O	I/O
204	I/O	I/O	I/O
205	NC	I/O	I/O
206	I/O	I/O	I/O
207	I/O	I/O	I/O
208	TCK, I/O	TCK, I/O	TCK, I/O

Note: * Note that Pin 65 in the A54SX32—PQ208 is a no connect (NC).

144-Pin TQFP			
Pin Number	A54SX08 Function	A54SX16P Function	A54SX32 Function
1	GND	GND	GND
2	TDI, I/O	TDI, I/O	TDI, I/O
3	I/O	I/O	I/O
4	I/O	I/O	I/O
5	I/O	I/O	I/O
6	I/O	I/O	I/O
7	I/O	I/O	I/O
8	I/O	I/O	I/O
9	TMS	TMS	TMS
10	V _{CCI}	V _{CCI}	V _{CCI}
11	GND	GND	GND
12	I/O	I/O	I/O
13	I/O	I/O	I/O
14	I/O	I/O	I/O
15	I/O	I/O	I/O
16	I/O	I/O	I/O
17	I/O	I/O	I/O
18	I/O	I/O	I/O
19	V _{CCR}	V _{CCR}	V _{CCR}
20	V _{CCA}	V _{CCA}	V _{CCA}
21	I/O	I/O	I/O
22	I/O	I/O	I/O
23	I/O	I/O	I/O
24	I/O	I/O	I/O
25	I/O	I/O	I/O
26	I/O	I/O	I/O
27	I/O	I/O	I/O
28	GND	GND	GND
29	V _{CCI}	V _{CCI}	V _{CCI}
30	V _{CCA}	V _{CCA}	V _{CCA}
31	I/O	I/O	I/O
32	I/O	I/O	I/O
33	I/O	I/O	I/O
34	I/O	I/O	I/O
35	I/O	I/O	I/O
36	GND	GND	GND

144-Pin TQFP			
Pin Number	A54SX08 Function	A54SX16P Function	A54SX32 Function
37	I/O	I/O	I/O
38	I/O	I/O	I/O
39	I/O	I/O	I/O
40	I/O	I/O	I/O
41	I/O	I/O	I/O
42	I/O	I/O	I/O
43	I/O	I/O	I/O
44	V _{CCI}	V _{CCI}	V _{CCI}
45	I/O	I/O	I/O
46	I/O	I/O	I/O
47	I/O	I/O	I/O
48	I/O	I/O	I/O
49	I/O	I/O	I/O
50	I/O	I/O	I/O
51	I/O	I/O	I/O
52	I/O	I/O	I/O
53	I/O	I/O	I/O
54	PRB, I/O	PRB, I/O	PRB, I/O
55	I/O	I/O	I/O
56	V _{CCA}	V _{CCA}	V _{CCA}
57	GND	GND	GND
58	V _{CCR}	V _{CCR}	V _{CCR}
59	I/O	I/O	I/O
60	HCLK	HCLK	HCLK
61	I/O	I/O	I/O
62	I/O	I/O	I/O
63	I/O	I/O	I/O
64	I/O	I/O	I/O
65	I/O	I/O	I/O
66	I/O	I/O	I/O
67	I/O	I/O	I/O
68	V _{CCI}	V _{CCI}	V _{CCI}
69	I/O	I/O	I/O
70	I/O	I/O	I/O
71	TDO, I/O	TDO, I/O	TDO, I/O
72	I/O	I/O	I/O

176-Pin TQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
137	I/O	I/O	I/O
138	I/O	I/O	I/O
139	I/O	I/O	I/O
140	V _{CCI}	V _{CCI}	V _{CCI}
141	I/O	I/O	I/O
142	I/O	I/O	I/O
143	I/O	I/O	I/O
144	I/O	I/O	I/O
145	I/O	I/O	I/O
146	I/O	I/O	I/O
147	I/O	I/O	I/O
148	I/O	I/O	I/O
149	I/O	I/O	I/O
150	I/O	I/O	I/O
151	I/O	I/O	I/O
152	CLKA	CLKA	CLKA
153	CLKB	CLKB	CLKB
154	V _{CCR}	V _{CCR}	V _{CCR}
155	GND	GND	GND
156	V _{CCA}	V _{CCA}	V _{CCA}

176-Pin TQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
157	PRA, I/O	PRA, I/O	PRA, I/O
158	I/O	I/O	I/O
159	I/O	I/O	I/O
160	I/O	I/O	I/O
161	I/O	I/O	I/O
162	I/O	I/O	I/O
163	I/O	I/O	I/O
164	I/O	I/O	I/O
165	I/O	I/O	I/O
166	I/O	I/O	I/O
167	I/O	I/O	I/O
168	NC	I/O	I/O
169	V _{CCI}	V _{CCI}	V _{CCI}
170	I/O	I/O	I/O
171	NC	I/O	I/O
172	NC	I/O	I/O
173	NC	I/O	I/O
174	I/O	I/O	I/O
175	I/O	I/O	I/O
176	TCK, I/O	TCK, I/O	TCK, I/O

313-Pin PBGA

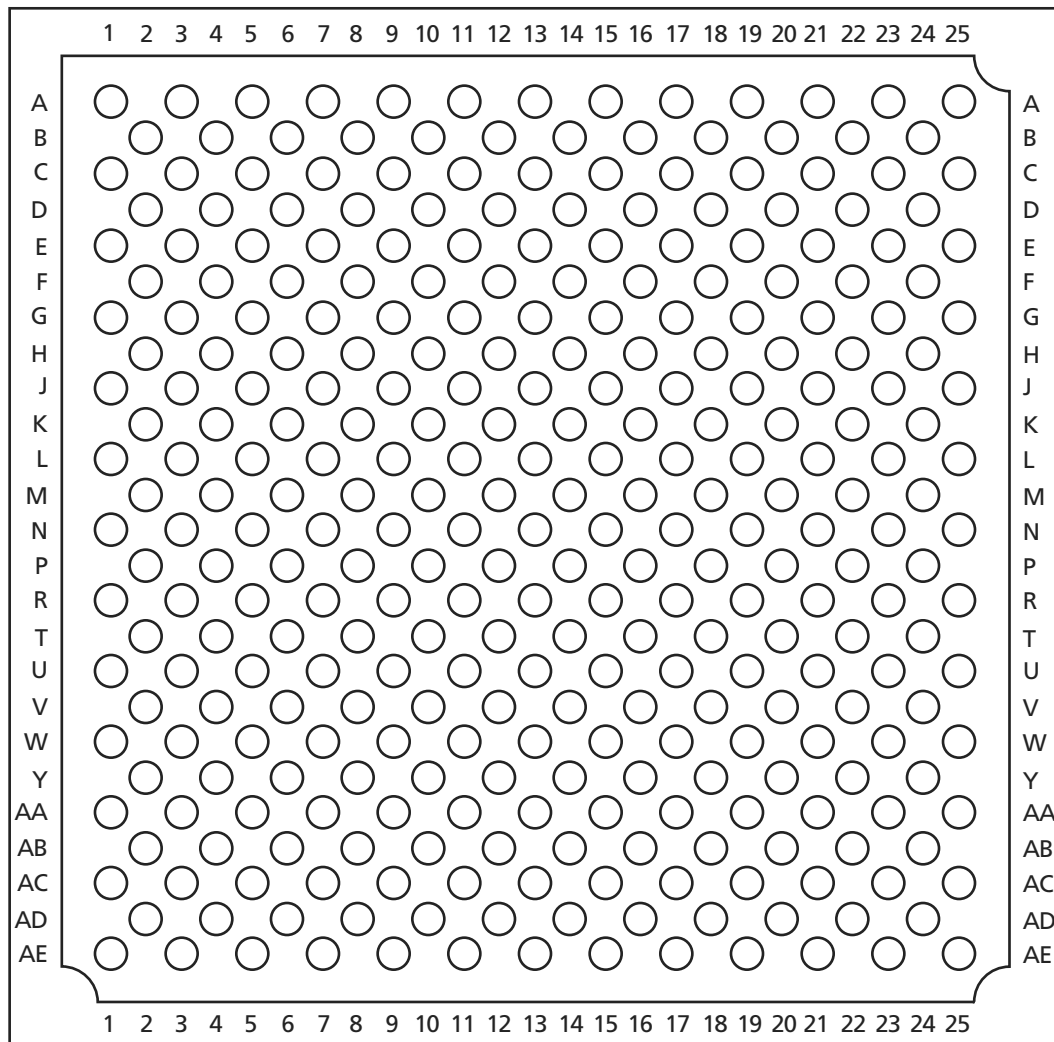


Figure 2-6 • 313-Pin PBGA (Top View)

Note

For Package Manufacturing and Environmental information, visit the Package Resource center at <http://www.actel.com/products/rescenter/package/index.html>.

313-Pin PBGA		313-Pin PBGA		313-Pin PBGA		313-Pin PBGA	
Pin Number	A54SX32 Function	Pin Number	A54SX32 Function	Pin Number	A54SX32 Function	Pin Number	A54SX32 Function
H20	I/O	L25	I/O	R5	I/O	V10	I/O
H22	V _{CCI}	M2	I/O	R7	I/O	V12	I/O
H24	I/O	M4	I/O	R9	I/O	V14	I/O
J1	I/O	M6	I/O	R11	I/O	V16	NC
J3	I/O	M8	I/O	R13	GND	V18	I/O
J5	I/O	M10	I/O	R15	I/O	V20	I/O
J7	NC	M12	GND	R17	I/O	V22	V _{CCA}
J9	I/O	M14	GND	R19	I/O	V24	V _{CCI}
J11	I/O	M16	V _{CCI}	R21	I/O	W1	I/O
J13	CLKA	M18	I/O	R23	I/O	W3	I/O
J15	I/O	M20	I/O	R25	I/O	W5	I/O
J17	I/O	M22	I/O	T2	I/O	W7	NC
J19	I/O	M24	I/O	T4	I/O	W9	I/O
J21	GND	N1	I/O	T6	I/O	W11	I/O
J23	I/O	N3	V _{CCA}	T8	I/O	W13	V _{CCI}
J25	I/O	N5	V _{CCR}	T10	I/O	W15	I/O
K2	I/O	N7	I/O	T12	I/O	W17	I/O
K4	I/O	N9	V _{CCI}	T14	HCLK	W19	I/O
K6	I/O	N11	GND	T16	I/O	W21	I/O
K8	V _{CCI}	N13	GND	T18	I/O	W23	I/O
K10	I/O	N15	GND	T20	I/O	W25	I/O
K12	I/O	N17	I/O	T22	I/O	Y2	I/O
K14	I/O	N19	I/O	T24	I/O	Y4	I/O
K16	I/O	N21	I/O	U1	I/O	Y6	I/O
K18	I/O	N23	V _{CCR}	U3	I/O	Y8	I/O
K20	V _{CCA}	N25	V _{CCA}	U5	V _{CCI}	Y10	I/O
K22	I/O	P2	I/O	U7	I/O	Y12	I/O
K24	I/O	P4	I/O	U9	I/O	Y14	I/O
L1	I/O	P6	I/O	U11	I/O	Y16	I/O
L3	I/O	P8	I/O	U13	I/O	Y18	I/O
L5	I/O	P10	I/O	U15	I/O	Y20	NC
L7	I/O	P12	GND	U17	I/O	Y22	I/O
L9	I/O	P14	GND	U19	I/O	Y24	NC
L11	I/O	P16	I/O	U21	I/O		
L13	GND	P18	I/O	U23	I/O		
L15	I/O	P20	NC	U25	I/O		
L17	I/O	P22	I/O	V2	V _{CCA}		
L19	I/O	P24	I/O	V4	I/O		
L21	I/O	R1	I/O	V6	I/O		
L23	I/O	R3	I/O	V8	I/O		

144-Pin FBGA

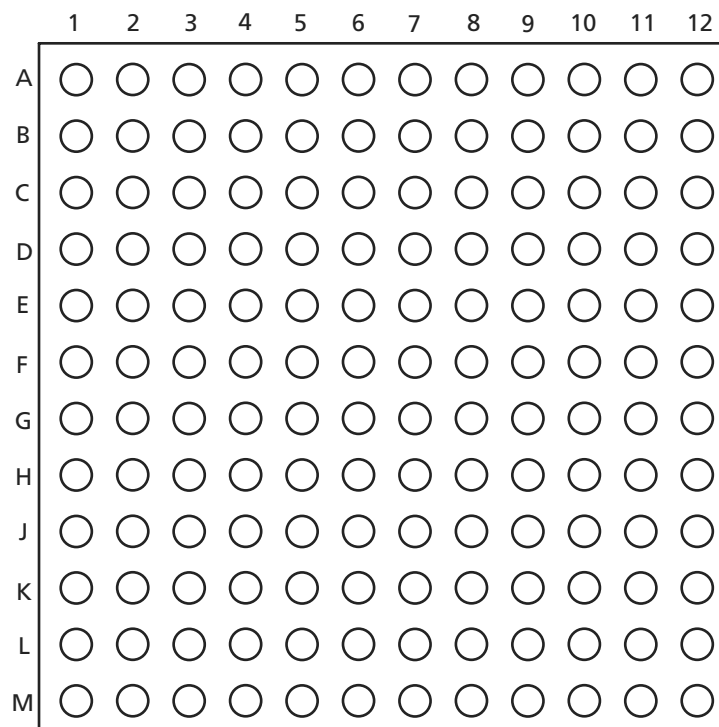


Figure 2-8 • 144-Pin FBGA (Top View)

Note

For Package Manufacturing and Environmental information, visit the Package Resource center at <http://www.actel.com/products/rescenter/package/index.html>.

144-Pin FBGA		144-Pin FBGA		144-Pin FBGA		144-Pin FBGA	
Pin Number	A54SX08 Function	Pin Number	A54SX08 Function	Pin Number	A54SX08 Function	Pin Number	A54SX08 Function
A1	I/O	D1	I/O	G1	I/O	K1	I/O
A2	I/O	D2	V _{CCI}	G2	GND	K2	I/O
A3	I/O	D3	TDI, I/O	G3	I/O	K3	I/O
A4	I/O	D4	I/O	G4	I/O	K4	I/O
A5	V _{CCA}	D5	I/O	G5	GND	K5	I/O
A6	GND	D6	I/O	G6	GND	K6	I/O
A7	CLKA	D7	I/O	G7	GND	K7	GND
A8	I/O	D8	I/O	G8	V _{CCI}	K8	I/O
A9	I/O	D9	I/O	G9	I/O	K9	I/O
A10	I/O	D10	I/O	G10	I/O	K10	GND
A11	I/O	D11	I/O	G11	I/O	K11	I/O
A12	I/O	D12	I/O	G12	I/O	K12	I/O
B1	I/O	E1	I/O	H1	I/O	L1	GND
B2	GND	E2	I/O	H2	I/O	L2	I/O
B3	I/O	E3	I/O	H3	I/O	L3	I/O
B4	I/O	E4	I/O	H4	I/O	L4	I/O
B5	I/O	E5	TMS	H5	V _{CCA}	L5	I/O
B6	I/O	E6	V _{CCI}	H6	V _{CCA}	L6	I/O
B7	CLKB	E7	V _{CCI}	H7	V _{CCI}	L7	HCLK
B8	I/O	E8	V _{CCI}	H8	V _{CCI}	L8	I/O
B9	I/O	E9	V _{CCA}	H9	V _{CCA}	L9	I/O
B10	I/O	E10	I/O	H10	I/O	L10	I/O
B11	GND	E11	GND	H11	I/O	L11	I/O
B12	I/O	E12	I/O	H12	V _{CCR}	L12	I/O
C1	I/O	F1	I/O	J1	I/O	M1	I/O
C2	I/O	F2	I/O	J2	I/O	M2	I/O
C3	TCK, I/O	F3	V _{CCR}	J3	I/O	M3	I/O
C4	I/O	F4	I/O	J4	I/O	M4	I/O
C5	I/O	F5	GND	J5	I/O	M5	I/O
C6	PRA, I/O	F6	GND	J6	PRB, I/O	M6	I/O
C7	I/O	F7	GND	J7	I/O	M7	V _{CCA}
C8	I/O	F8	V _{CCI}	J8	I/O	M8	I/O
C9	I/O	F9	I/O	J9	I/O	M9	I/O
C10	I/O	F10	GND	J10	I/O	M10	I/O
C11	I/O	F11	I/O	J11	I/O	M11	TDO, I/O
C12	I/O	F12	I/O	J12	V _{CCA}	M12	I/O

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